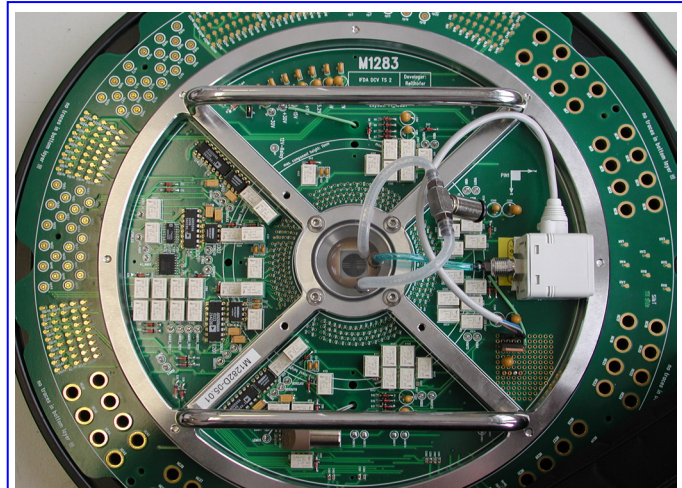


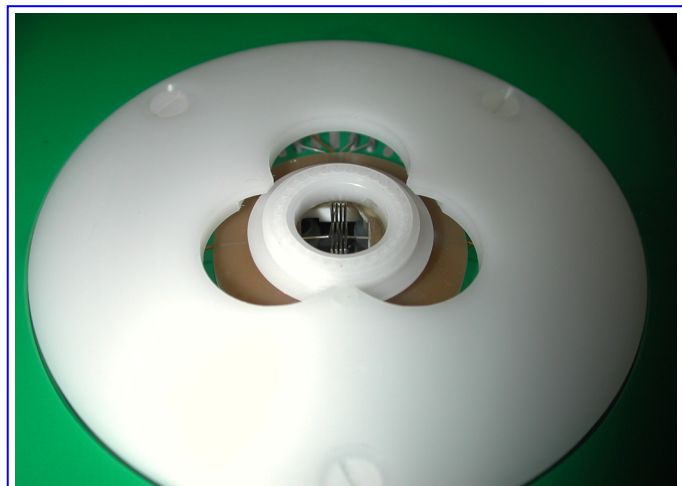
Probe Cards for Sensor Devices

T.I.P.S. can provide "add-on's" to conventional cantilever probe cards to enable wafer test of sensor ICs:

- **Pressure sensors:** a chip scale pressure chamber allows to exert air pressure for pressure sensors or other gas atmosphere. The pressure chamber is hovering over the wafer surface creating a micro gap seal and is not touching the wafer surface
- **Humidity sensors:** specially designed and leakage protected probe cards allow the creation of an atmosphere with defined humidity for testing CMOS humidity sensors
- Probe cards for testing **magnetic fields, radioactivity sensors, CMOS imaging sensors...**



Probe card for pressure sensor IC test
quad site parallel testing



Probe card for humidity sensor with
chip scale chamber